

WORKSHOP: Advanced SPM for Materials Investigation Napoli 19 Giugno



Vi invitiamo a partecipare al Workshop "Advanced SPM for Material Investigation", che organizzeremo insieme all'Università Federico II di Napoli, CNR SPIN e Park System AFM, durante la giornata del 19 di Giugno 2019.

Luogo dell'evento: Università Federico II di Napoli sede di Ingegneria della Scuola Politecnica e delle Scienze di Base (Aula Bobbio) in P. le Tecchio.

Potete aderire inviando una e-mail alla Sig.ra Stefania Fabbri stefania.fabbri@gambetti.it, oppure telefonandoci al numero 02 90093082.

Programma

Time	Item	Description/ Title
09:30	Registration	
10:00	Welcome & Introduction	Local Host Università di Napoli Federico II Dip. Di Fisica e C.N.R. SPIN Introduction by Prof. Antonio Cassinese
10:15	Scientific Talk I	Scanning Kelvin Probe microscopy on organic thin film transistors <i>Dr. Fabio Chiarella, SPIN-CNR Naples</i>
10:35	Scientific Talk II	Scanning Probe Microscopy and Spectroscopy on Oxides <i>Dr. Marco Salluzzo, CNR-SPIN</i>
10:55	Scientific Talk III	Scanning near field optical microscopy and spectroscopy on two dimensional materials

Dr. Felice Gesuele Dept. Of Physics University of Naples

- 11:05 Scientific Talk IV Piezoelectric Characterization of AlN thin films by Piezoresponse Force Microscopy
Dr.ssa Tiziana Stomeo, Center for Bio-Molecular Nanotechnology – Istituto Italiano di Tecnologia (IIT)
- 11:35 Coffee break
- 12:00 Featured talk Enhanced Surface Potential Detection using Frequency Modulation SKPM
Dr. Andrea Cerreta, Park Systems Europe
- 12:20 Scientific Talk V Morphological characterization of LAO/STO micro-membranes
Prof. Roberto di Capua University of Naples Federico II
- 12:40 Scientific Talk VI Nanoscale characterization of visco-hyperelastic cell membranes with atomic force spectroscopy microscopy)
Prof. Luciano Lamberti, Politecnico of Bari
- 13:00 Scientific Talk VII Elasto-mechanical study of MoS₂ domes by Atomic Force Microscopy and Spectroscopy
Prof. Fabrizio Bobba University of Salerno
- 13:20 Lunch
- 14:20 AFM Instrumentation Demo Park Systems NX10 AFM
- 15:20 Round Table Discussion Most advanced research trends